

Application/Control No.	Applicant(s)/Patent under Reexamination	Applicant(s)/Patent under Reexamination	
	VAN DEN MEERAKKER ET AL.		
Examiner	Art Unit		
Mahmoud Dahimene	1765		

	SEAR	CHED	
Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
·	DATE	EXMR	
EAST Search (US-PGPUB, USPAT, USOCR, EPO, JPO, Derwent, IBM-TDB) Search notes attached.	9/14/2006	MD	
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